

RU1HE3H-VB Datasheet N-Channel 100 V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}\left(\Omega\right)$	I _D (A) ^d	Q _g (Typ.)			
100	0.124 at V _{GS} = 10 V	4.2	4.6 nC			
100	0.128 at V _{GS} = 4.5 V	3.9	4.6 nC			

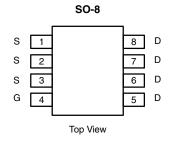
FEATURES

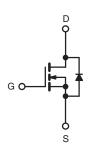
- Trench Power MOSFET
- 100 % UIS Tested

ROHS COMPLIANT HALOGEN FREE

APPLICATIONS

- High Frequency Boost Converter
- LED Backlight for LCD TV





N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T _A = 25 °C, unless otherwise noted)						
Parameter	Symbol	Limit	Unit			
Drain-Source Voltage	V_{DS}	100	V			
Gate-Source Voltage	V_{GS}	± 20	v			
Continuous Drain Current (T _J = 150 °C)	$T_C = 25 ^{\circ}\text{C}$ $T_C = 70 ^{\circ}\text{C}$ $T_A = 25 ^{\circ}\text{C}$	I _D	4.2 3.5 3.0 ^{a, b}			
$T_{A} = 70 ^{\circ}\text{C}$ Pulsed Drain Current $T_{C} = 25 ^{\circ}\text{C}$		I _{DM}	2.4 ^{a, b} 16 4.0	Α		
Continuous Source-Drain Diode Current	T _A = 25 °C	- I _S	2 ^{a, b}			
Single Avalanche Current L = 0.1 mH		I _{AS}	6	Α		
Single Avalanche Energy		E _{AS}	1.8	mJ		
Maximum Power Dissipation	$T_{C} = 25 ^{\circ}\text{C}$ $T_{C} = 70 ^{\circ}\text{C}$ $T_{A} = 25 ^{\circ}\text{C}$ $T_{A} = 70 ^{\circ}\text{C}$	P _D	4.8 3 2.4 ^{a, b} 1.5 ^{a, b}	w		
Operating Junction and Storage Temperatur	T _J , T _{stg}	- 55 to 150	°C			

THERMAL RESISTANCE RATINGS							
Parameter		Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient ^{a, c}	t ≤ 10 s	R _{thJA}	42	53	°C/W		
Maximum Junction-to-Foot (Drain)	Steady State	R_{thJF}	21	26			

Notes:

- a. Surface mounted on 1" x 1" FR4 board.
- b. t = 10 s.
- c. Maximum under steady state conditions is 85 $^{\circ}\text{C/W}.$
- d. Based on T_C = 25 °C.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static			I.		l	_
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	100			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		110		mV/°C
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 7.5		
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	1		3	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zana Oata Wallana Busin Oamant	I _{DSS}	V _{DS} = 100 V, V _{GS} = 0 V			1	
Zero Gate Voltage Drain Current		V _{DS} = 100 V, V _{GS} = 0 V, T _J = 55 °C			10	μΑ
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	8			Α
_		$V_{GS} = 10 \text{ V}, I_D = 2.7 \text{ A}$	0.124 0.128			Ω
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_D = 2.5 \text{ A}$				
Forward Transconductance ^a	g _{fs}	$V_{DS} = 10 \text{ V}, I_D = 2.7 \text{ A}$		7		S
Dynamic ^b						
Input Capacitance	C _{iss}			470		
Output Capacitance	C _{oss}	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		50		pF
Reverse Transfer Capacitance	C _{rss}			25		
Total Gate Charge	Q _g	$V_{DS} = 50 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 2.7 \text{ A}$		7.1	11	nC
	Q g −			4.6	7	
Gate-Source Charge	Q_{gs}	$V_{DS} = 50 \text{ V}, V_{GS} = 6 \text{ V}, I_{D} = 2.7 \text{ A}$		1.7		
Gate-Drain Charge	Q_{gd}			2		
Gate Resistance	R_g	f = 1 MHz		3		Ω
Turn-On Delay Time	t _{d(on)}			10	15	
Rise Time	t _r	V_{DD} = 50 V, R_L = 23.8 Ω		10	15	ns
Turn-Off Delay Time	t _{d(off)}	$I_D\cong$ 2.1 A, V_{GEN} = 6 V, R_g = 1 Ω		10	15	
Fall Time	t _f			10	15	
Turn-On Delay Time	t _{d(on)}			10	15	
Rise Time	t _r	V_{DD} = 50 V, R_L = 23.8 Ω		10	15	
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 2.1$ A, V_{GEN} = 10 V, R_g = 1 Ω		12	20	
Fall Time	t _f			10	15	1
Drain-Source Body Diode Characteristi	cs					
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			4	Δ
Pulse Diode Forward Current	I _{SM}				8	Α
Body Diode Voltage	V_{SD}	I _S = 2.1 A, V _{GS} = 0 V		0.8	1.2	V
Body Diode Reverse Recovery Time	t _{rr}			50	80	ns
Body Diode Reverse Recovery Charge	Q_{rr}	I _F = 2.1 A, dI/dt = 100 A/μs, T _J = 25 °C		75	120	nC
Reverse Recovery Fall Time	ta	1F - 2.1 A, αι/αι = 100 A/μS, 1J = 25 °C		28		
Reverse Recovery Rise Time	t _b	t _b		22		ns

Notes:

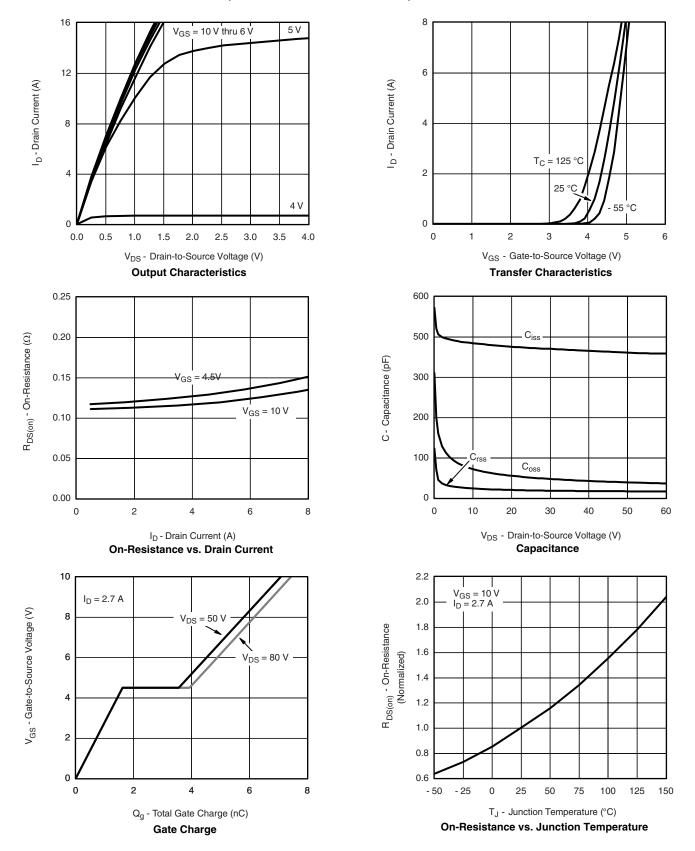
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- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



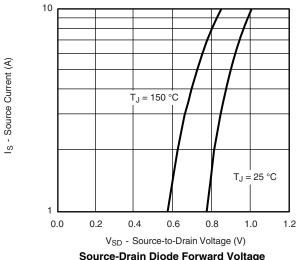
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

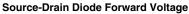


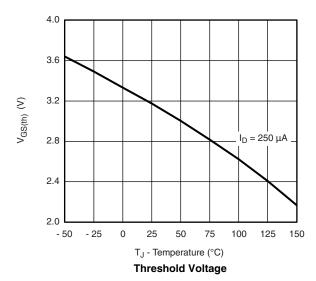
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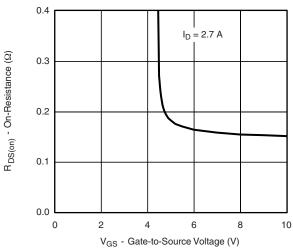


TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

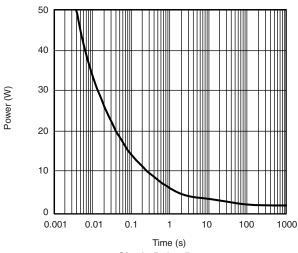




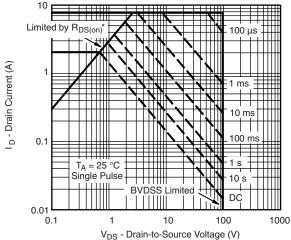




On-Resistance vs. Gate-to-Source Voltage



Single Pulse Power

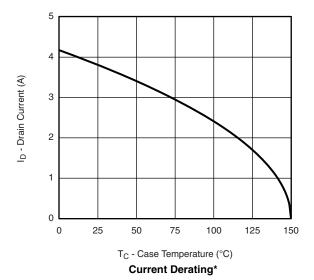


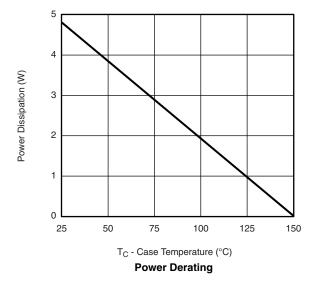
* $V_{GS} > \mbox{minimum} \ V_{GS}$ at which $R_{DS(on)}$ is specified

Safe Operating Area, Junction-to-Ambient



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

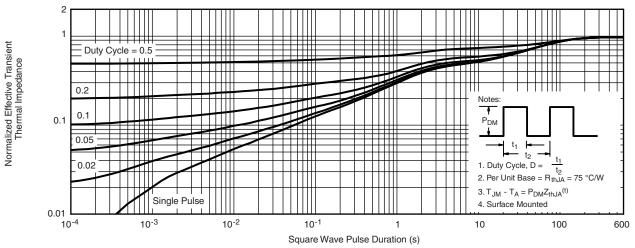




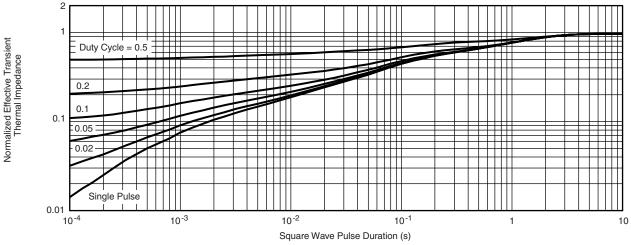
^{*} The power dissipation P_D is based on $T_{J(max.)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



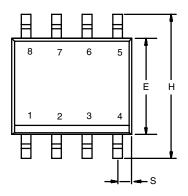
Normalized Thermal Transient Impedance, Junction-to-Ambient

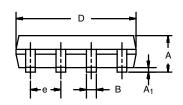


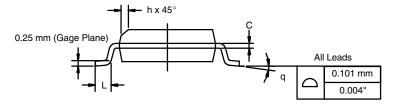
Normalized Thermal Transient Impedance, Junction-to-Foot



SOIC (NARROW): 8-LEAD JEDEC Part Number: MS-012







	MILLIMETERS		S INCHES		
DIM	Min	Max	Min	Max	
Α	1.35	1.75	0.053	0.069	
A ₁	0.10	0.20	0.004	0.008	
В	0.35	0.51	0.014	0.020	
С	0.19	0.25	0.0075	0.010	
D	4.80	5.00	0.189	0.196	
E	3.80	4.00	0.150	0.157	
е	1.27 BSC		0.050 BSC		
Н	5.80	6.20	0.228	0.244	
h	0.25	0.50	0.010	0.020	
L	0.50	0.93	0.020	0.037	
q	0°	8°	0°	8°	
S	0.44	0.64	0.018	0.026	
FONL C 00507 Part L 11 Car 00					

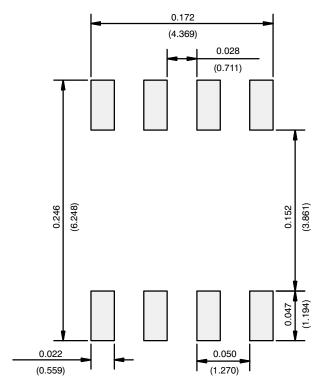
ECN: C-06527-Rev. I, 11-Sep-06

DWG: 5498

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RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)



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